Test generation with structurally synthesized BDD models
Raik, Jaan; **Ubar, Raimund-Johannes** Proceedings of the 5th Electronic Devices and Systems Conference, Brno, June 11-12, 1998 1998 / p. 66-68

VHDL based test generation system
Jervan, Gert; **Markus, Antti**; **Raik, Jaan**; **Ubar, Raimund-Johannes** Proceedings of the 5th Electronic Devices and Systems Conference, Brno, June 11-12, 1998 1998 / p. 145-148